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tes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/791,787	XIAOYU ET AL.	
	Examiner	Art Unit	
	Tamai I.E. Karl	2834	

SEARCHED			
Class	Subclass	Date	Examiner
310	309		
359	223-226		
	290, 291	3/10/2006	KIT

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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